| Ref<br>#  | Hits | Search Query  | DBs                | Default<br>Operator | Plurals | Time Stamp       |
|-----------|------|---|--------------------|---------------------|---------|------------------|
| <b>L1</b> | 49   | ("6295623" "6374392" "5745767" "4400663" "6311043" "5371851" "6226765" "6226765" "5226048" "5805610" "5668477" "5347518" "6233182" "6467056" "6113645" "6287765" "5859963" "6034948" "6512988" "6678643" "5696772" "5726996" "5920490" "6249891" "6061283" "6308292" "6651205" "4931723" "4994732" "5376849" "5748642" "5931953" "5931952" "5935256" "4327572" "5570383" "5604751" "6060898" "6101622" "6360343" "6377065" "6445208" "6557133" "6594609" "6668331" "5212443" "5477139" "6184048" "5371457" "4291404").pn. | US-PGPUB;<br>USPAT | OR                  | ON      | 2004/12/09 09:42 |

## 10624614\_CLS.txt Most Frequently Occurring Classifications of Patents Returned From A Search of 10624614 on December 07, 2004

```
Original Classifications
       714/724
       714/738
       324/158.1
       324/765
       713/400
       714/38
714/718
Cross-Reference Classifications
       324/73.1
714/724
       365/201
       713/500
714/738
714/741
   4
       324/158.1
       713/502
714/731
       714/736
       714/742
       714/744
       703/22
703/27
       714/39
       714/735
Combined Classifications
      714/724
 12
       714/738
324/73.1
       324/158.1
       365/201
713/500
714/741
                                                                                                          erm
                                                                      CRM
       714/731
       324/765
703/22
713/400
   3
                                                                                                12
       713/502
       714/38
   33332222222222
       714/736
                                              707/3,14,15,16,19
714/28,30,724,731,728
702/117,119,119,120,122 (23)
702/117,119,119,120,122 (23)
       714/742
       714/744
365/200
702/117
                                                                                                  778 1741
       702/123
       703/27
       714/32
       714/39
       714/718
714/730
       714/735
       716/6
```

## 10624614\_CLSTITLES.txt Titles of Most Frequently Occurring Classifications of Patents Returned From A Search of 10624614 on December 07, 2004

```
12 714/724
                    (7 \text{ OR}, 5 \text{ XR})
                   714 : ERROR DETECTION/CORRECTION AND FAULT
         Class
                            DETECTION/RECOVERY
          714/699
                         PULSE OR DATA ERROR HANDLING
                          .Digital logic testing
          714/724
                   (5 OR, 4 XR)
714 : ERROR DETECTION/CORRECTION AND FAULT
  714/738
          Class
                            DETECTION/RECOVERY
          714/699
                         PULSE OR DATA ERROR HANDLING
          714/724
                         .Digital logic testing
          714/738
                          .. Including test pattern generator
         3.1 (1 OR, 5 XR)
Class 324 : ELECTRICITY: MEASURING AND TESTING
   324/73.1
          324/73.1
                         PLURAL, AUTOMATICALLY SEQUENTIAL TESTS
         .58.1 (2 OR, 3 XR)
Class 324: ELECTRICITY: MEASURING AND TESTING
    324/158.1
          324/158.1
                         MISCELLANEOUS
                 (1 OR, 4 XR)
365 : STATIC INFORMATION STORAGE AND RETRIEVAL
          Class
          365/189.01
                         READ/WRITE CIRCUIT
          365/201
                         .Testing
                    (1 OR, 4 XR)
   713/500
                   713 : ELECTRICAL COMPUTERS AND DIGITAL PROCESSING
         Class
                            SYSTEMS: SUPPORT
                         CLOCK, PULSE, OR TIMING SIGNAL GENERATION OR
         713/500
                             ANALYSIS
                    (1 OR, 4 XR)
 5 714/741
          class
                   714 : ERROR DETECTION/CORRECTION AND FAULT
                            DETECTION/RECOVERY
         714/699
714/724
                         PULSE OR DATA ERROR HANDLING .Digital logic testing
          714/738
                          ..Including test pattern generator
                          ...Simulation
          714/741
                    (1 \text{ OR}, 3 \text{ XR})
   714/731
                   714: ERROR DETECTION/CORRECTION AND FAULT DETECTION/RECOVERY
         class
          714/699
                         PULSE OR DATA ERROR HANDLING .Digital logic testing
          714/724
          714/726
                          ...Scan path testing (e.g., level sensitive scan
                              design (LSSD))
          714/731
                          ...Clock or synchronization
                   (2 OR, 1 XR)
324 : ELECTRICITY: MEASURING AND TESTING
 3 324/765
          Class
          324/500
                         FAULT DETECTING IN ELECTRIC CIRCUITS AND OF
                               ELECTRIC COMPONENTS
                          .Of individual circuit component or element
          324/537
          324/765
                          .. Test of semiconductor device
                   (1 OR, 2 XR)
703 : DATA PROCESSING: STRUCTURAL DESIGN,
 3 703/22
         Class
                            MODELING, SIMULATION, AND EMULATION
```

```
10624614_CLSTITLES.txt
        703/13
                        SIMULATING ELECTRONIC DEVICE OR ELECTRICAL
                             SYSTEM
        703/22
                         .Software program (i.e., performance
                            prediction)
 713/400
                   (2 OR, 1 XR)
        Class
                         ELECTRICAL COMPUTERS AND DIGITAL PROCESSING
                           SYSTEMS: SUPPORT
        713/400
                        SYNCHRONIZATION OF CLOCK OR TIMING SIGNALS,
                            DATA, OR PULSES
  713/502
                   (0 \text{ or}, 3 \text{ XR})
                         ELECTRICAL COMPUTERS AND DIGITAL PROCESSING
                  713:
        Class
                           SYSTEMS: SUPPORT
        713/500
                        CLOCK, PULSE, OR TIMING SIGNAL GENERATION OR
                             ANALYSIS
        713/502
                         .Counting, scheduling, or event timing
                   (2 OR, 1 XR)
  714/38
                         ERROR DETECTION/CORRECTION AND FAULT
        Class
                  714:
                           DETECTION/RECOVERY
                        DATA PROCESSING SYSTEM ERROR OR FAULT HANDLING
        714/100
                         .Reliability and availability
         714/1
         714/25
                         ...Fault locating (i.e., diagnosis or testing)
                         ...Analysis (e.g., of output, state, or design)
        714/37
        714/38
                         ....Of computer software
  714/736
                   (0 \text{ OR}, 3 \text{ XR})
                  714 : ERROR DETECTION/CORRECTION AND FAULT DETECTION/RECOVERY
        Class
                         PULSE OR DATA ERROR HANDLING
         714/699
         714/724
                         .Digital logic testing
         714/736
                         ..Device response compared to expected
                            fault-free response
  714/742
                   (0 \text{ OR}, 3 \text{ XR})
                         ERROR DETECTION/CORRECTION AND FAULT DETECTION/RECOVERY
         Class
                  714:
                         PULSE OR DATA ERROR HANDLING
         714/699
        714/724
714/738
                         .Digital logic testing
                        ...Including test pattern generator ....Testing specific device
         714/742
                  (0 OR, 3 XR)
714: ERROR DETECTION/CORRECTION AND FAULT
3
  714/744
        Class
                           DETECTION/RECOVERY
                        PULSE OR DATA ERROR HANDLING
         714/699
        714/724
714/738
                        .Digital logic testing
                         ..Including test pattern generator
                         ... Clock or synchronization
         714/744
                  (1 OR, 1 XR)
365 : STATIC INFORMATION STORAGE AND RETRIEVAL
  365/200
         Class
         365/189.01
                        READ/WRITE CIRCUIT
         365/200
                         .Bad bit
  702/117
                   (1 \text{ OR}, 1 \text{ XR})
        Class
                  702 :
                         DATA PROCESSING: MEASURING, CALIBRATING, OR
                           TESTING
        702/108
                        TESTING SYSTEM
```

## 10624614\_CLSTITLES.txt 702/117 .Of circuit 2 702/123 (1 OR, 1 XR) 702 : DATA PROCESSING: MEASURING, CALIBRATING, OR class **TESTING** 702/108 TESTING SYSTEM 702/123 .Including program set up 2 703/27 (0 OR, 2 XR)Class 703: DATA PROCESSING: STRUCTURAL DESIGN. MODELING, SIMULATION, AND EMULATION 703/23 **EMULATION** .Compatibility emulation 703/27 714/32 2 (1 OR, 1 XR) class 714 : ERROR DETECTION/CORRECTION AND FAULT DETECTION/RECOVERY 714/100 DATA PROCESSING SYSTEM ERROR OR FAULT HANDLING 714/1 .Reliability and availability 714/25 ...Fault locating (i.e., diagnosis or testing) 714/32 ...Particular stimulus creation (0 OR, 2 XR) 14: ERROR DETECTION/CORRECTION AND FAULT 2 714/39 714: class DETECTION/RECOVERY 714/100 DATA PROCESSING SYSTEM ERROR OR FAULT HANDLING 714/1 .Reliability and availability 714/25 .. Fault locating (i.e., diagnosis or testing) 714/37 ...Analysis (e.g., of output, state, or design) ....Monitor recognizes sequence of events 714/39 (e.g., protocol or logic state analyzer) 2 714/718 (2 OR, 0 XR)ERROR DETECTION/CORRECTION AND FAULT Class DETECTION/RECOVERY 714/699 PULSE OR DATA ERROR HANDLING 714/718 .Memory testing 714/730 (1 OR, 1 XR)ERROR DETECTION/CORRECTION AND FAULT Class 714 : **DETECTION/RECOVERY** PULSE OR DATA ERROR HANDLING .Digital logic testing 714/699 714/724 ..Scan path testing (e.g., level sensitive scan 714/726 design (LSSD)) 714/730 ... Addressing 714/735 (0 OR, 2 XR)class 714: ERROR DETECTION/CORRECTION AND FAULT DETECTION/RECOVERY 714/699 PULSE OR DATA ERROR HANDLING 714/724 .Digital logic testing 714/735 ..Device response compared to input pattern

716: DATA PROCESSING: DESIGN AND ANALYSIS OF CIRCUIT OR SEMICONDUCTOR MASK

716/6

class

716/1

(1 OR, 1 XR)

CIRCUIT DESIGN

|       | 10624614_CLSTITLES.txt                             |  |
|-------|--|--|
| 716/4 | .Testing or evaluating                             |  |
| 716/5 | Design verification (e.g., wiring line             |  |
| -     | capacitance, fan-out checking, minimum path width) |  |
| 716/6 | Timing analysis (e.g., delay time, path            |  |
| -     | delay, latch timing)                               |  |

PLUS Search Results for S/N 10624614, Searched December 07, 2004

The Patent Linguistics Utility System (PLUS) is a USPTO automated search system for U.S. Patents from 1971 to the present. PLUS is a query-by-example search system which produces a list of patents that are most closely related linguistically to the application searched. This search was prepared by the staff of the Scientific and Technical Information Center, SIRA.

## 10624614\_QUAL.txt